Applications of Artificial Intelligence, Machine Learning, Deep Learning, and Explainable AI (XAI)

Guest Editors:

Dr. Pratheepan Yogarajah

Dr. Muthu Subash Kavitha

Dr. Lamiaa Abdel-Hamid

Dr. Ananthakrishnan Balasundaram

Deadline for manuscript submissions:
15 January 2025

Message from the Guest Editors

Artificial intelligence (AI) with machine learning and deep learning models has been widely applied in numerous domains, including medical imaging, healthcare, industrial manufacturing, sports, and many more. In recent years, many efforts have been made to improve the interpretability of the decisions of machine learning and deep learning algorithms. Explainable Artificial Intelligence (XAI) has been established as a new research area, which aims to provide new methodologies and algorithms to enhance transparency and reliability to both the decisions made by predictive algorithms and the contributions and importance of individual features to the outcome.

The purpose of this Special Issue is to report on the advances in state-of-the-art research on artificial intelligence machine learning, deep learning, and explainable AI applications. The advances in the state-of-the-art for addressing real-world AI applications are of great interest.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, and other databases.
Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us